Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/798,658	CHANG ET AL.	
	Examiner	Art Unit	
	J. Derek Rutten	2192	

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Class	Subclass	Date	Examiner
717	131	6/4/2007	JDR

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Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Invnentor name search PLUS search	6/1/2007	JDR
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